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| <b>Notice of References Cited</b> | Application/Control No.<br>10/713,154 | Applicant(s)/Patent Under<br>Reexamination<br>LIU, YEN-FU |             |
|                                   | Examiner<br>Douglas N. Washburn       | Art Unit<br>2863  | Page 1 of 1 |

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